Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/672,880	BISKEBORN ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	417 603.11 603.13- 603.16	6/12/2006	PK
	603.18		
216	65		
360	121 126 129		
	316 317		
427	127 128	/	
451	5,41	V	

INT	TERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
Reviewed Parent Application 09/877382 (US PAT. 6,646,830)	6/12/2006	PK	
Text Search EAST/NPL (IEEE)	6/12/2006	PK	